

SPECTROMETRY SOLUTIONS ARTAX μXRF SPECTROMETER



ARTAX – Elemental Analysis for the Art Community and More...

Non-destructive elemental analysis is strictly required for testing many kinds of samples. Origin or age determination of unique and

- valuable art objects Investigations on objects that secure evidence in
- forensic sciences
- Final testing of industrial products Materials research, especially when a limited
- amount of sample is available or material recovery is essential

Micro X-ray fluorescence analysis (µXRF) is the most suitable technology for these requirements.

μXRF delivers the most detailed information

- possible on the materials composition and/or
- Objects are not damaged or altered by µXRF
- The analysis can be done at the location of the object of interest with a mobile configuration of the spectrometer

Bruker AXS offers a complete range of μ XRF spectrometers. Different configurations are available to meet your application and budgetary needs.

	ri prescence	X-Ray Fluorescence Analysis (XRF)	
	Micro X-ray Fluorescence	1 11:41	
X-Ray Microanalysis	Analysis (perting	Capability Elemental analysis of bulk	
(EDS)	Capability	Elemenial and y samples	
	Le atructive spund	samples	
alution element	investigation	Limitation	
High resolution in the sub-µm range	distribution	c action about span	
IN the set y	Limitation	No information element distribution	-
Limitation	Limitation Analytical range of 10 µm to	eleme	
Limitation Destructive sample preparation	10 mm		
required			
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	Contraction of the second	(175)	
		cm.	
the state of the s		mm - cm	
and a second	<u>μm - mm</u>		
	μπ		
<u>nm - μ</u> m			

The ARTAX is the first portable X-ray fluorescence (XRF) spectrometer designed to meet the specific requirements for non-destructive elemental analysis.

ARTAX is suitable for multielement analysis of Na(11) to U(92) and offers a spatial resolution down to 70 μ m. Fast, highresolution elemental analysis is possible with ARTAX because of its innovative measuring head design.

The ability to combine ARTAX options into a system uniquely tailored to your needs ensures maximum flexibility for a wide range of applications.

- Archeometry
- Restoration and conservation
- Process-related quality control
- Forensic sciences Research and development of advanced
- materials



Illuion	immovable
	User benefits Direct, on the spot examination of valuable or immovable
	Used the spot examination -
ARTAX features	Direct, on mean
AKIAKT	objects tion of large und a
ARTAX teutor Portable instrument design	Direct, on the spot examination objects Enables the examination of large and uneven objects
	Enables the examination of the examination of the examination required No sample preparation required to solution Possible the reduces measurement
Compact, open system	intensity read
tocusing	Highest spanse fluorescence mense,
i sillary lens for beam local o	No sample preparation required No sample preparation possible Highest spatial resolution possible Extremely high fluorescence intensity reduces measurement
Polycapillary lens for beam focusing	antholiog
	Liquid nitrogen as course in short measurement Na(11) to Ar(18)
XFlash [®] Silicon Drift Detector (SDD	High count rate results in the lements from Na(197) High count rate reasurement of light elements from Na(197) Immediate measurement of light damage fragile samples Avoids vacuum, which might damage fragile samples
XElash [®] Silicon DIM D	
	Immediate which might dame
Helium purging	Immediate measure Avoids vacuum, which might damage was Avoids vacuum, which might damage was Reproducible positioning of the measuring head
Hellulli perg	Reproducible position
	·

XYZ stage

The Heart of ARTAX – the Measuring Head







The ARTAX is equipped with a measuring head featuring the most advanced technology for precise and fast data acquisition.

Outstanding components include the XFlash® Silicon Drift Detector (SDD) and an innovative exchangeable excitation source.

The polycapillary lens of the ARTAX creates a microspot (< 100 μ m) of primary X-radiation with high intensity. Polycapillary lenses are an ensemble of several thousand glass capillaries which form a united monolithic structure.

In comparison to a pinhole collimator, the fluorescence intensity of a polycapillary lens is increased by a factor of more than 1000.

The XFlash[®] energy-dispersive detector analyses the X-ray fluorescence. This Peltier cooled silicon drift detector operates nitrogenfree with high-speed, low-noise electronics. It has significantly better energy resolution and higher count rates than PIN diode detectors. This allows fast measurements during line scans

and element mappings.

	PIN diode	XFlash
% Deadtime at 2,500 cps at 25,000 cps	> 20 % > 75 %	< 0.5 % < 6 %
Energy resolution	> 200 eV	< 160 eV opt. < 145 eV

The integrated CCD camera shows a magnified image of the sample region under investigation. A white LED illuminates the sample to optimise the image quality and contrast. Pictures are automatically stored for documentation purposes.

Change Your Excitation - it's as Simple as That !

The excitation source is fitted with a high precision lock, which allows the fast exchange of the X-ray tube housing. This enables you to choose the most suitable excitation and quickly exchange the X-ray optics. Including warm-up, the switch of the tube can be done in less than

15 minutes. Mo or W? Both! An X-ray tube with a W target generates 2 to 5 times larger peak areas for K-line elements above 20 keV (e.g. Ag, Sn, Sb) than one with a Mo target. In contrast, Sb) than one with a Mo target in contrast, and the Mo tube has the major advantage of the Mo tube has the major advantage of significantly better light element detection. The ARTAX allows the fast and easy application of both W and Mo X-ray target materials for advanced analysis of any kind of sample.

The exact position of the beam on the sample and the exact distance between object and spectrometer is controlled via a laser diode. The laser spot is adjusted to the focus of the mini-lens and is visualised by the camera.

The movement of the measuring head is controlled by a XYZ stage, which is suitable for fast line scans and element mappings. Powerful software creates area images of the element distribution across the sample.

distribution ucross and The open design of the spectrometer head together with a distance of about 10 mm to the sample enables access to uneven or structured samples.







- A touch sensor immediately triggers an emergency stop of the XYZ stage when the head moves too close to the sample
- Easy integration of additional warning lamps, door interlocks, etc.
- Integrated flow controller for the He purge control and "empty bottle" alarm

Successful in Art, Forensics and Industry



Tissue with gun shot residue

Three Solutions – No Analytical Compromise

The outstanding performance of the ARTAX is based on the design of the measuring head and the integration of the most modern components. The same measuring head is included in all ARTAX systems. This guarantees the highest data quality –

without compromise. Exchangeable excitation source with air-cooled

- Liquid nitrogen-free XFlash[®] Silicon Drift X-ray tube
- Detector, 160 eV resolution
- Integrated CCD camera with sample illumination and laser spot
- Compact control unit including high voltage ARTAXControl for semi-quantitative XRF analysis

Users have different requirements for their μ XRF spectrometer: the number of samples, the analytical procedure, the need of mobility and the financial resources.

Consequentially Bruker AXS offers three ARTAX configurations, each fully upgradable at any time.

ARTAX 200 – Small labs with a limited number of samples, independent conservators, high

need for mobility ARTAX 400 – Labs with medium requirements,

- need for 1D and 2D mappings ARTAX 800 – Labs with high-level requirements,
- numerous samples, fast sample thoughput

The ability to customize your ARTAX as needed ensures that it will meet your requirements now and in the future.

Accessories for the ARTAX systems Second excitation source, tube housing, X-ray tube, collimator or polycapillary lens, target of

- your choice (W, Rh, Cu, Ti) Additional filter assembly for improving the
- signal to noise ratio Collimator set: 0.2 mm, 1.0 mm, 1.5 mm
- Acrylic glass shielding for protection against
- scattering





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BRUKER ADVANCED X-RAY SOLUTIONS

Specifications of the ARTAX systems	200	400	800
Basic system			
Compact control unit with high voltage generator, 50 kV, 50 W	\checkmark	✓	✓
Option for light element detection starting from Na Helium gas flow of the excitation and detection paths	option	~	✓
Measuring head			
Colour CCD camera, 500x582 pixel, ca. 20 times magnification Dimmable white LED for sample illumination Laser spot for reproducible positioning of the measuring head	✓	✓	✓
Detector			
Peltier cooled XFlash [®] Silicon Drift Detector, 10 mm ² active area Energy resolution < 160 eV for Mn-Kα at 100 kcps Max. count rate > 100 kcps, dead time < 10% at 40 kcps	\checkmark	✓	V
Detector upgrade, energy resolution < 145 eV, Mn-Kα at 100 kcps	_	option	option
Exchangeable excitation source			
X-ray tube housing with precision lock for simple exchange Incl. electro-mechanical shutter, two absorption filters	\checkmark	✓	~
Air-cooled Mo X-ray fine focus tube*, max. 50V, 1 mA, 50W Exchangeable collimator, 650μm	\checkmark	✓	_
Air-cooled Mo X-ray micro focus tube*, max. 50 V, 1 mA, 30 W Polycapillary lens for micro excitation spot (intensity gain > 1000) Lateral resolution < 100μm, for excitation up to Sb K-line	_	_	~
Mounting			
Tripod for free positioning of the system, incl. rolling scates Free rotatable arm and variable height adjustment (500 to 1500 mm)	_	✓	✓
XYZ stage with stepper motors, 50 mm range ARTAX 1D and 2D mapping software	_	✓	✓
Light-weight tripod, optimally suited for mobile use	\checkmark	option	option
Software			
ARTAXControl semi-quantitative XRF software for hardware control and data evaluation	\checkmark	~	✓
ARTAXQuant standards-based software	option	option	option
Notebook computer	option	✓	✓

* W, Rh, Cu and Ti tubes available on request

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